

ID	Description	Attribute Data	Units
1	Raw Read Error Rate	0	Errors/Page
5	Reallocated NAND Block Count	0	NAND Blocks
9	Power On Hours Count	118	Hours
12	Power Cycle Count	136	Power Cycles
171	Program Fail Count	0	NAND Page Program Failures
172	Erase Fail Count	0	NAND Block Erase Failures
173	Block Wear-Leveling Count	2	Erases
174	Unexpected Power Loss Count	1	Unexpected Power Loss events
180	Unused Reserved Block Count	45	Blocks
183	SATA Interface Downshift	0	Downshifts
184	Error Correction Count	0	Correction Events
187	Reported Uncorrectable Errors	0	ECC Correction Failures
194	Enclosure Temperature	47	Current Temperature (C)
		60	Highest Lifetime Temperature (C)
196	Reallocation Event Count	0	Events
197	Current Pending ECC Count	0	ECC Counts
198	SMART Off-line Scan Uncorrectable Errors	0	Errors
199	Ultra-DMA CRC Error Count	0	Errors
202	Percentage Lifetime Remaining	100	% Lifetime Remaining
206	Write Error Rate	0	Program Fails/MB
210	RAIN Successful Recovery Page Count	0	TUs successfully recovered by RAIN
246	Cumulative Host Sectors Written	1154221589	512 Byte Sectors
247	Host Program Page Count	18490583	NAND Page
248	FTL Program Page Count	33783513	NAND Page